

Enhancement Mode N-Channel Power MOSFET

PDFN5X6/NMOS/60V/ \pm 20V/1.8V/50A/12m Ω

Rev_{0.1}





60V, 12mΩ, 50A, N-Channel Enhancement MOSFET

1.Features

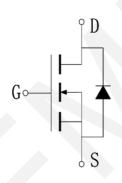
- ♦ 60V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±20V
- ◆ 100% RG Tested
- ◆ 100% UIS Tested

2.Applications

- Power Switching Application
- ◆ Load Switching



V _{DS}	R _{DS(on)} Typ.	I _D Max.	
60V	12mΩ @ 10V	504	
	18mΩ @ 4.5V	50A	



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WX012N06PA	012N06	PDFN5X6	5,000	50,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V_{DSS}	60	V
Gate to Source Voltage	V_{GSS}	±20	V
Drain Current (DC)	I _D	50	Α
Drain Current (Pulse), PW≤300μs	I _{DP}	200	А
Total Dissipation	P_{D}	35	W
Avalanche Energy, Single Pulsed	E _{AS}	150	mJ
Junction Temperature	T _j	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Junction to Case	$R_{ heta JC}$	3.6	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

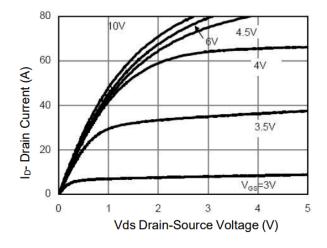
6.Electrical Characteristics at Ta=25°C (Note 3)

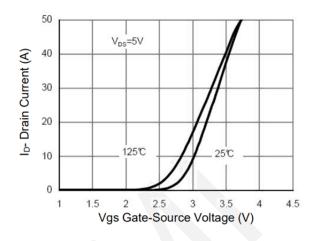
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	60	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V_{DS} =60V, V_{GS} = 0V	-	-	1	μA
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$	ı	-	±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{DS}=250\mu A$	1.2	1.8	2.2	V
Static Drain to Source On-State	D	I _D =30A, V _{GS} = 10V		12	18	mΩ
Resistance	R _{DS(on)}	$I_D = 20A, V_{GS} = 4.5V$	-	18	23	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,	-	2050	-	pF
Output Capacitance	C_{oss}	V _{DS} =30V,	-	158	-	pF
Reverse Transfer Capacitance	C _{rss}	Frequency=1.0MHz	1	120	-	pF
Turn-ON Delay Time	t _{d(on)}		ı	7.4	-	ns
Rise Time	t _r	$V_{DD} = 30V, R_{L} = 6.7\Omega,$	-	5.1	-	ns
Turn-OFF Delay Time	$t_{\text{d(off)}}$	$V_{GS} = 10V, R_{GEN} = 3\Omega$	-	28.2	-	ns
Fall Time	t _f		-	5.5	-	ns
	Q_g	V _{DS} =30V, V _{GS} = 10V,	-	50	-	nC
Total Gate Charge	Q_{gs}		-	6	-	nC
	Q_{gd}	I _D =20A	-	15	-	nC
Diode Forward Voltage	V_{FSD}	I _S =30A, V _{GS} = 0V	-	-	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

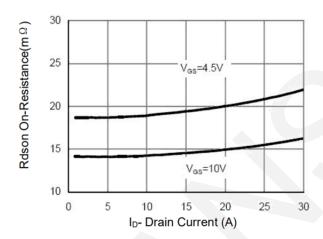


7. Typical electrical and thermal characteristics

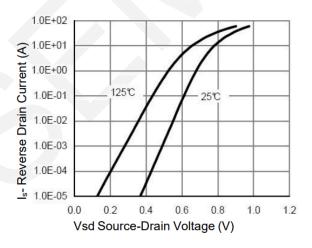




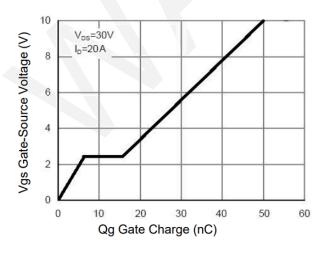
Output Characteristics



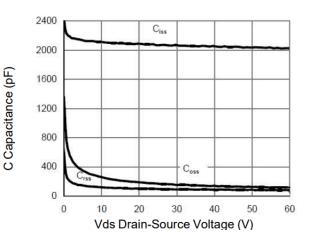
Typical Transfer Characteristics



On-resistance vs. Drain Current



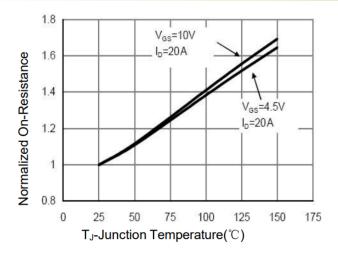
Body Diode Characteristics

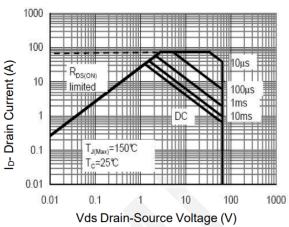


Gate Charge Characteristics

Capacitance Characteristics



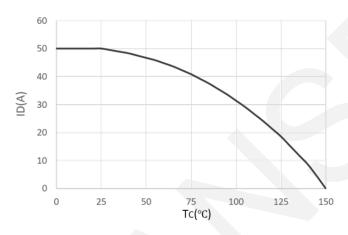




Normalized on Resistance vs.

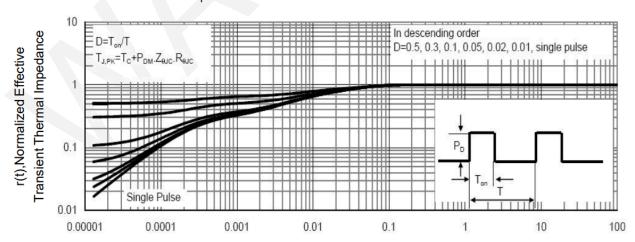
Junction Temperature

Maximum Safe Operating Area



Maximum Continuous Drain Current vs.

Case Temperature

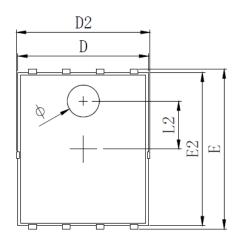


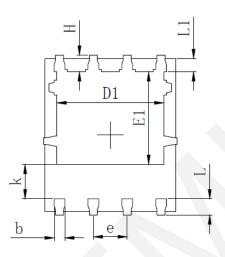
Square Wave Pluse Duration (sec)

Maximum Effective Transient Thermal Impedance, Junction-to-Case



8.Package Dimensions





SYMBOL		MILLIMETER		
SIMDOL	MIN	Тур.	MAX	
A	0. 900	1. 000	1. 100	
A1	0.254 REF.			
A2		0~0.05		
D	4. 824	4. 900	4. 976	
D1	3. 910	4. 010	4. 110	
D2	4. 924	5. 000	5. 076	
Е	5. 924	6. 000	6. 076	
E1	3. 375	3. 475	3. 575	
E2	5. 674	5. 750	5. 826	
b	0. 350	0. 400	0. 450	
e	1.270 TYP.			
L	0. 534	0. 610	0. 686	
L1	0. 424	0. 500	0. 576	
L2	1.800 REF.			
k	1. 190	1. 290	1. 390	
Н	0. 549	0. 625	0. 701	
θ	8°	10°	12°	
ф	1. 100	1. 200	1.300	
d			0. 100	



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